## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination FRITZ ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0043404	03-2003	Fetherolf et al.	358/1.15
*	В	US-2004/0150803	08-2004	Boldon, John Leland	355/018
*	С	US-2001/0005269	06-2001	Nozawa, Shinji	358/1.12
*	D	US-2002/0105663	08-2002	Pappalardo et al. 358/	
*	Ε	US-2002/0131065	09-2002	Sweetland et al.	358/1.13
*	F	US-6,493,743	12-2002	Suzuki, Hideo	709/203
*	G	US-7,173,724	02-2007	Nomura et al.	358/1.15
*	Н	US-6,781,709	08-2004	Nozawa, Shinji	358/1.12
*	ı	US-6,934,915	08-2005	Rudd et al. 715/	
*	J	US-7,065,562	06-2006	Courtney, Mike	709/220
*	K	US-6,959,329	10-2005	Thakor, Sanjiv	709/220
*	L	US-6,674,537	01-2004	Kadowaki, Toshihiro 358/	
*	М	US-2004/0012628	01-2004	Kropf et al.	345/744

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				·	
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*						
		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
1	٧					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.